1. Features

Low-voltage and Standard-voltage Operation

- 1.8 (V_{CC} = 1.8V to 5.5V)

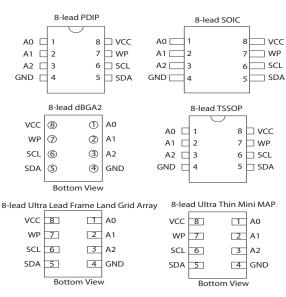
- Internally Organized as 16,384 x 8
- Two-wire Serial Interface
- Schmitt Trigger, Filtered Inputs for Noise Suppression
- Bidirectional Data Transfer Protocol
- 1 MHz (5.5V, 2.5V), and 400 kHz (1.8V) Compatibility
- Write Protect Pin for Hardware and Software Data Protection
- 64-byte Page Write Mode (Partial Page Writes Allowed)
- Self-timed Write Cycle (5 ms Max)
- High Reliability
 - Endurance: One Million Write Cycles
 - Data Retention: 40 Years
- Lead-free/Halogen-free
- 8-lead JEDEC PDIP, 8-lead JEDEC SOIC, 8-lead Ultra Thin Mini MAP, 8-lead Ultra Lead Frame Land Grid Array (ULA), 8-lead TSSOP, and 8-ball dBGA2 Packages
- Die Sales: Wafer Form, Tape and Reel and Bumped Wafers

2. Description

The AT24C128B provides 131,072 bits of serial electrically erasable and programmable read-only memory (EEPROM) organized as 16,384 words of 8 bits each. The device's cascadable feature allows up to eight devices to share a common two-wire bus. The device is optimized for use in many industrial and commercial applications where low-power and low-voltage operation are essential. The devices are available in space-saving 8-lead JEDEC PDIP, 8-lead JEDEC SOIC, 8-lead Ultra Thin Mini MAP, 8-lead Ultra Lead Frame Land Grid Array (ULA), 8-lead TSSOP, and 8-ball dBGA2 packages. In addition, the entire family is available in a 1.8V (5.5V to 3.6V) version.

Table 0-1. Pin Configurations

Pin Name	Function
A0–A2	Address Inputs
SDA	Serial Data
SCL	Serial Clock Input
WP	Write Protect
GND	Ground





Two-wire Serial EEPROM

128K (16,384 x 8)

AT24C128B





3. Absolute Maximum Ratings*

Operating Temperature55°C to +125°C
Storage Temperature65°C to +150°C
Voltage on Any Pin with Respect to Ground1.0V to +7.0V
Maximum Operating Voltage 6.25V
DC Output Current 5.0 mA

*NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

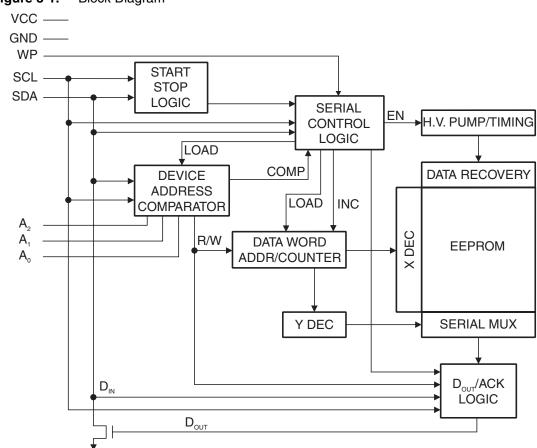


Figure 3-1. Block Diagram



5. Memory Organization

AT24C128B, 128K SERIAL EEPROM: The 128K is internally organized as 256 pages of 64 bytes each. Random word addressing requires a 14-bit data word address.

Table 5-1.Pin Capacitance⁽¹⁾

Applicable over recommended operating range from $T_A = 25^{\circ}C$, f = 1.0 MHz, $V_{CC} = +1.8V$ to 5.5V

Symbol	Test Condition	Max	Units	Conditions
C _{I/O}	Input/Output Capacitance (SDA)	8	pF	$V_{I/O} = 0V$
C _{IN}	Input Capacitance (A ₀ , A ₁ , SCL)	6	pF	$V_{IN} = 0V$

Note: 1. This parameter is characterized and is not 100% tested.

Table 5-2.DC Characteristics

Applicable over recommended operating range from: $T_{AI} = -40^{\circ}C$ to $+85^{\circ}C$, $V_{CC} = +1.8V$ to +5.5V (unless otherwise noted)

Symbol	Parameter	Test Condition		Min	Тур	Max	Units
V _{CC1}	Supply Voltage			1.8		5.5	V
I _{CC1}	Supply Current	$V_{CC} = 5.0 V$	READ at 400 kHz		1.0	2.0	mA
I _{CC2}	Supply Current	$V_{CC} = 5.0V$	WRITE at 400 kHz		2.0	3.0	mA
1	Standby Current (1.8V option)	$V_{\rm CC} = 1.8 V$				1.0	μA
I _{SB1}		$V_{CC} = 5.5V$	$V_{\rm IN} = V_{\rm CC} \text{ or } V_{\rm SS}$			6.0	μA
I _{LI}	Input Leakage Current V _{CC} = 5.0V	$V_{IN} = V_{CC} \text{ or } V_{SS}$			0.10	3.0	μA
I _{LO}	Output Leakage Current $V_{CC} = 5.0V$	$V_{OUT} = V_{CC} \text{ or } V_{SS}$			0.05	3.0	μA
V _{IL}	Input Low Level ⁽¹⁾			- 0.6		V _{CC} x 0.3	V
V _{IH}	Input High Level ⁽¹⁾			V _{CC} x 0.7		V _{CC} + 0.5	V
V _{OL2}	Output Low Level	$V_{\rm CC} = 3.0 V$	I _{OL} = 2.1 mA			0.4	V
V _{OL1}	Output Low Level	$V_{CC} = 1.8V$	I _{OL} = 0.15 mA			0.2	V

Notes: 1. $V_{\rm IL}$ min and $V_{\rm IH}$ max are reference only and are not tested.

Table 5-3. AC Characteristics (Industrial Temperature)

	Parameter	1.8-volt		2.5, 5.5-volt		
Symbol		Min	Max	Min	Max	Units
f _{SCL}	Clock Frequency, SCL		400		1000	kHz
t _{LOW}	Clock Pulse Width Low	1.3		0.4		μs
t _{HIGH}	Clock Pulse Width High	0.6		0.4		μs
ti	Noise Suppression Time ⁽¹⁾		100		50	ns
t _{AA}	Clock Low to Data Out Valid	0.05	0.9	0.05	0.55	μs
t _{BUF}	Time the bus must be free before a new transmission can start ⁽¹⁾	1.3		0.5		μs
t _{HD.STA}	Start Hold Time	0.6		0.25		μs
t _{SU.STA}	Start Set-up Time	0.6		0.25		μs
t _{HD.DAT}	Data In Hold Time	0		0		μs
t _{SU.DAT}	Data In Set-up Time	100		100		ns
t _R	Inputs Rise Time ⁽¹⁾		0.3		0.3	μs
t _F	Inputs Fall Time ⁽¹⁾		300		100	ns
t _{SU.STO}	Stop Set-up Time	0.6		0.25		μs
t _{DH}	Data Out Hold Time	50		50		ns
t _{WR}	Write Cycle Time		5		5	ms
Endurance ⁽¹⁾	25°C, Page Mode, 3.3V	1,000,000			Write Cycles	

Applicable over recommended operating range from $T_{AI} = -40^{\circ}$ C to $+85^{\circ}$ C, $V_{CC} = +1.8$ V to +5.5V, CL = 100 pF (unless otherwise noted). Test conditions are listed in Note 2.

Notes: 1. This parameter is ensured by characterization and is not 100% tested.

2. AC measurement conditions:

 R_L (connects to V_{CC}): 1.3 k Ω (2.5V, 5.5V), 10 k Ω (1.8V) Input pulse voltages: 0.3 V_{CC} to 0.7 V_{CC} Input rise and fall times: \leq 50 ns Input and output timing reference voltages: 0.5 V_{CC}





10. AT24C128B Ordering Information

Ordering Code	Voltage	Package	Operation Range		
AT24C128B-PU (Bulk Form Only)	1.8	8P3			
AT24C128BN-SH-B ⁽¹⁾ (NiPdAu Lead Finish)	1.8	8S1			
AT24C128BN-SH-T ⁽²⁾ (NiPdAu Lead Finish)	1.8	8S1			
AT24C128B-TH-B ⁽¹⁾ (NiPdAu Lead Finish)	1.8	8A2	Lead-free/Halogen-free Industrial Temperature		
AT24C128B-TH-T ⁽²⁾ (NiPdAu Lead Finish)	1.8	8A2	(-40°C to 85°C)		
AT24C128BY6-YH-T ⁽²⁾ (NiPdAu Lead Finish)	1.8	8Y6			
AT24C128BD3-DH-T ⁽²⁾ (NiPdAu Lead Finish)	1.8	8D3			
AT24C128BU2-UU-T ⁽²⁾	1.8	8U2-1			
AT24C128B-W-11 ⁽³⁾	1.8	Die Sale	Industrial Temperature (-40°C to 85°C)		

Notes: 1. "-B" denotes bulk.

2. "-T" denotes and tape and reel. SOIC = 4K. TSSOP, dBGA2, and Mini MAP = 5k. SAP = 3K.

3. Available in tape and reel and wafer form; order as SL788 for inkless wafer form. Bumped die available upon request. Please contact Serial Interface Marketing.

Package Type				
8P3	8-lead, 0.300" Wide, Plastic Dual Inline Package (PDIP)			
8S1	8-lead, 0.150" Wide, Plastic Gull Wing Small Outline Package (JEDEC SOIC)			
8A2	8-lead, 0.170" Wide, Thin Shrink Small Outline Package (TSSOP)			
8Y6	8-lead, 2.00 mm x 3.00 mm Body, 0.50 mm Pitch, Ultra Thin Mini MAP, Dual No Lead Package, (DFN), (MLP2x3mm)			
8D3	8-lead, 1.80 mm x 2.20 mm Body, Ultra Lead Frame Land Grid Array (ULA)			
8U2-1	8-ball, die Ball Grid Array Package (dBGA2)			
Options				
-1.8	Low-voltage (1.8V to 5.5V)			

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8A2 - TSSOP

